				Sheet <u>1</u> of 1		
FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE	ATTY. DOCKET NO.		SERIAL NO.		
	PATENT AND TRADEMARK OFFICE	107348-00385		10/731,438		
AP OFFERENCE	APPLICANT					
USI OF REFERENCES	S CITED BY APPLICANT	KIKUCHI et al.				
Hilse several sh	APR 2 1 2004 (Use several sheets if necessary)			GROUP		
APR 2 1 2004				2817		
THE STATE OF THE S	U.S. PATENT DOCUMENT	S				
FXAMINE			0110	511.00		

	U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	EMA	DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
A	AA	5,731,779	03/24/1998	Kikuchi	342	70	12/17/1996
	AB	6,122,040	09/19/2000	Arita et al.	356	4.01	10/30/1998
V	AC	6,229,597 B1	05/08/2001	Kikuchi	356	4.01	07/14/1999
	AD						
	AE						
	AF						

FOREIGN	PATENT	DOCUMENTS
----------------	--------	------------------

	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TR/ YES	ANSLAT NO F	ION PART.
AG								
АН								
AI								
LA L								
AK								
AL								

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

d	#	АМ	Patent Abstracts of Japan for Pub. No. 2000 258527, published Sept. 22, 2000; For: Adjusting Method for Radar Axis of Radar Apparatus for Vehicle and Radar Apparatus for Vehicle; Applicant: Hitachi Ltd.
/	1	AN	Patent Abstracts of Japan for Pub. No. 09304535, published Nov. 28, 1997; For: Apparatus and Method for Measurement; Applicant: Omron Corp.
		AO	

EXAMINER	I dan	DATE CONSIDERED 8/30/05
*FXAMINER:	Initial if reference concidered, whather or not citation is i	a conformance with MACO COD Devution through citation if not in

CARIVITYER. Initial it reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not it conformance and not considered. Include copy of this form with next communication to applicant.

236888_1.DOC

FO	RM	PI	TO-1	44	9

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.	SERIAL NO.
107348-00385	New
APPLICANT	
KIKUCHI	
FILING DATE	GROUP

Unknown

December 10, 2003

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

		IMFNT	

			- O.O. TATELL	1 DOCCIMENTO			
EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	AA						·
	AB						
	AC		<u> </u>				
	AD						
	AE						<u> </u>
	AF						_

FOREIGN PATENT DOCUMENTS

	•	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	NSLAT	
PA	AG	3114849	9/22/2000	Japan			х	
	AH	2000-258527	9/29/2000	Japan			x	
	Al							
	AJ							
	AK							
	AL							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.) AM AN AO

EXAMINER	DATE CONSIDERED
*EVANIALED: Initial if and an analysis of the state of th	

Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.